



Product Change Notification / GBNG-16BGIH897

Date:

27-Jan-2022

Product Category:

Ethernet Bridges, USB Hubs

PCN Type:

Manufacturing Change

Notification Subject:

CCB 4628 and 4628.001 Final Notice: Qualification of STA as an additional assembly site for selected LAN9500A, USB2512B, USB2513B, USB2514B and USX2064 device families available in 56L VQFN (8x8x0.9mm) and 36L VQFN (6x6x1.0mm) packages.

Affected CPNs:

[GBNG-16BGIH897_Affected_CPN_01272022.pdf](#)

[GBNG-16BGIH897_Affected_CPN_01272022.csv](#)

Notification Text:

PCN Status:Final Notification

PCN Type:Manufacturing Change

Microchip Parts Affected:Please open one of the files found in the Affected CPNs section.

Note: For your convenience Microchip includes identical files in two formats (.pdf and .xls)

Description of Change:Qualification of STA as an additional assembly site for selected LAN9500A, USB2512B, USB2513B, USB2514B and USX2064 device families available in 56L VQFN (8x8x0.9mm) and 36L VQFN (6x6x1.0mm) packages.

Pre and Post Change Summary:

Final PCN Issue Date																		x				
Estimated Implementation Date												x										

Method to Identify Change:Traceability code

Qualification Report:Please open the attachments included with this PCN labeled as PCN_#_Qual_Report.

Revision History:May 12, 2021: Issued initial notification.

October 8, 2021: Issued final notification. Provided estimated first ship date to be on October 31, 2021. Updated the estimated qualification completion date from August 2021 to December 2021.

December 7, 2021: Re-issued final notification. Attached the Qualification Report.

January 27, 2022: Re-issued final notification. Corrected lead frame drawing for ASE 36L VQFN in the Pre and Post Change summary attachment.

The change described in this PCN does not alter Microchip’s current regulatory compliance regarding the material content of the applicable products.

Attachments:

[PCN_GBNG-16BGIH897_Pre_and_Post Change Summary.pdf](#)

[PCN_GBNG-16BGIH897_Qual Report.pdf](#)

Please contact your local [Microchip sales office](#) with questions or concerns regarding this notification.

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MICROCHIP

**QUALIFICATION REPORT SUMMARY
RELIABILITY LABORATORY**

PCN #: GBNG-16BGIH897

**Date:
November 15, 2021**

Qualification of STA as an additional assembly site for selected LAN9500A, USB2512B, USB2513B, USB2514B and USX2064 device families available in 56L VQFN (8x8x0.9mm) and 36L VQFN (6x6x1.0mm) packages.



MICROCHIP PACKAGE QUALIFICATION REPORT

Purpose	Qualification of STA as an additional assembly site for selected LAN9500A, USB2512B, USB2513B, USB2514B and USX2064 device families available in 56L VQFN (8x8x0.9mm) and 36L VQFN (6x6x1.0mm) packages.
CCB	4628 and 4628.001
CN	ES361343
QUAL ID	R2100819 Rev. A
MP CODE	XG571SRTXB0C
Part No.	LAN9500A-ABZJ-TR
Bonding No.	BDM-002967 Rev. A
<u>Package</u>	
Type	56L VQFN
Package size	8x8x0.9 mm
<u>Lead Frame</u>	
Paddle size	236 x 236 mils
Material	C194
Surface	Double Ring
Process	Etched
Lead Lock	No
Part Number	R002-3646X
<u>Material</u>	
Epoxy	8290
Wire	CuPdAu wire
Mold Compound	G700E
Plating Composition	Matte Sn



Manufacturing Information

Assembly Lot No.	Wafer Lot No.	Date Code
STA-221300020.000	GF07922071569.100	21256RJ
STA-221300022.000	GF07922071569.100	21266RQ
STA-221300021.000	GF07922071569.100	21256RK

Result

Pass Fail _____

56L VQFN (8x8x0.9 mm) assembled by STA pass reliability test per QCI-39000. This package was qualified the Moisture/Reflow Sensitivity Classification Level 3 at 260°C reflow temperature per IPC/JEDEC J-STD-020E standard.

PACKAGE QUALIFICATION REPORT

Test Number (Reference)	Test Condition	Standard/ Method	Qty. (Acc.)	Def/SS	Result	Remarks
Precondition Prior Perform Reliability Tests (At MSL Level 3)	Electrical Test: +25°C and 100°C System: EX_ANALOG	JESD22-A113	693(0)	693		Good Devices
	Bake 150°C, 24 hrs System: CHINEE	JIP/IPC/JEDEC		693		
	30°C/60%RH Moisture Soak 192 hrs. System: TABAI ESPEC Model PR-3SPH	J-STD-020E		693		
	3x Convection-Reflow 265°C max			693		
	System: Vitronics Soltec MR1243					
Electrical Test: +25°C and 100°C System: EX_ANALOG			0/693	Pass		

PACKAGE QUALIFICATION REPORT

Test Number (Reference)	Test Condition	Standard/ Method	Qty. (Acc.)	Def/SS.	Result	Remarks
Temp Cycle	Stress Condition: -65°C to +150°C, 500 Cycles System: TABAI ESPEC TSA-70H	JESD22-A104		231		Parts had been pre-conditioned at 260°C 77 units / lot
	Electrical Test: +100°C System: EX_ANALOG		231(0)	0/231	Pass	
	Stress Condition: -65°C to +150°C, 1000 Cycles System: TABAI ESPEC TSA-70H			231		
	Electrical Test: +100°C System: EX_ANALOG		231(0)	0/231	Pass	
	Bond Strength: Wire Pull (> 3.00 grams) Bond Shear (> 8.00 grams)		15 (0)	0/15	Pass	
			15 (0)	0/15	Pass	
UNBIASED-HAST	Stress Condition: +130°C/85%RH, 96 hrs. System: HAST 6000X	JESD22-A118		231		Parts had been pre-conditioned at 260°C 77 units / lot
	Electrical Test: +25°C System: EX_ANALOG		231(0)	0/231	Pass	
	Stress Condition: +130°C/85%RH, 192 hrs. System: HAST 6000X			231		
	Electrical Test: +25°C System: EX_ANALOG		231(0)	0/231	Pass	

PACKAGE QUALIFICATION REPORT

Test Number (Reference)	Test Condition	Standard/ Method	Qty. (Acc.)	Def/SS.	Result	Remarks
High Temperature Storage Life	Stress Condition: Bake 175°C, 504 hrs System: SHEL LAB	JESD22-A103		45		45 units
	Electrical Test: +25°C and 100°C System: EX_ANALOG		45(0)	0/45	Pass	
Solderability Temp 245°C	Steam Aging: Temp 93°C,8Hrs System: SAS-3000 Solder Dipping:Solder Temp.245°C Solder material:Pb Free Sn 95.5Ag3.9 Cu0.6 System: ERSA RA 2200D Visual Inspection: External Visual Inspection	J-STD-002	22 (0)	22 22 0/22	Pass	
Physical Dimensions	Physical Dimension, 10 units from 1 lot	JESD22-B100/B108	30(0) Units	0/30	Pass	
Bond Strength Data Assembly	Wire Pull (> 3.00 grams)	Mil. Std. 883-2011	30 (0) Wires	0/30	Pass	
	Bond Shear (> 8.00 grams)	CDF-AEC-Q100-001	30 (0) bonds	0/30	Pass	

CCB 4628 and 4628.001
Pre and Post Change Summary
PCN #: GBNG-16BGIH897



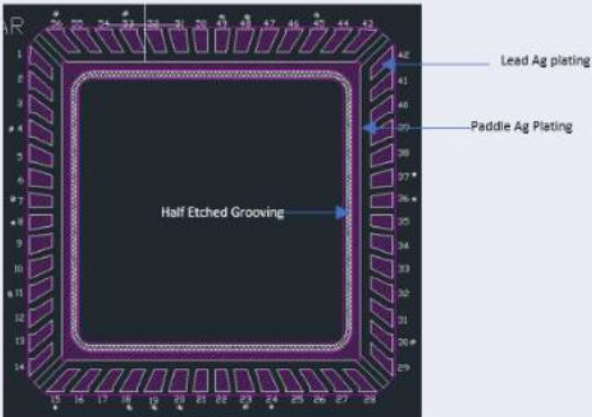
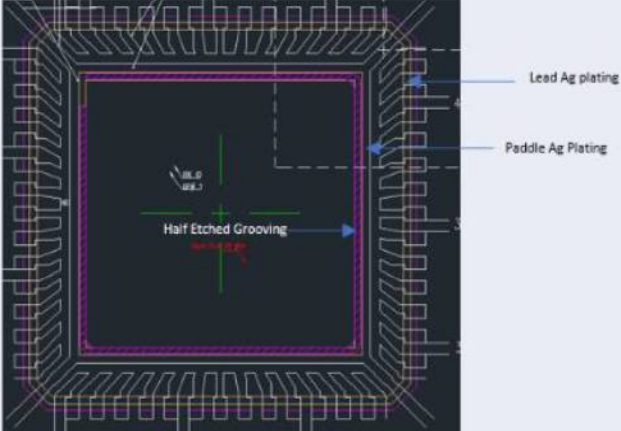
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SMART | CONNECTED | SECURE

Lead frame Comparison

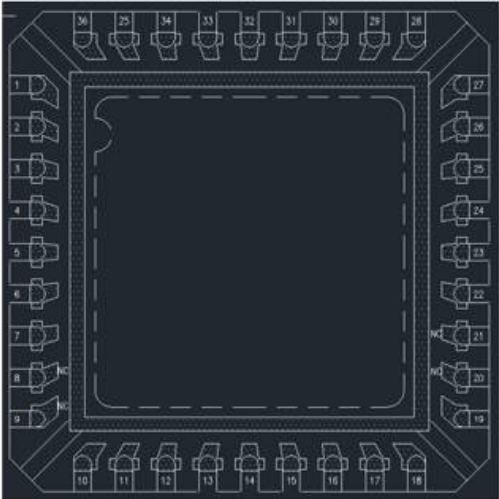
56L VQFN

ASE	STA
LF Definition – Double Ring Plating	LF Definition – Double Ring Plating
<p>*Plating on Lead finger and plating surrounding LF Paddle (Purple shaded area)</p>  <p>Lead Ag plating</p> <p>Paddle Ag Plating</p> <p>Half Etched Grooving</p>	<p>*Plating on Lead finger and plating surrounding LF Paddle (Yellow outline area)</p>  <p>Lead Ag plating</p> <p>Paddle Ag Plating</p> <p>Half Etched Grooving</p>

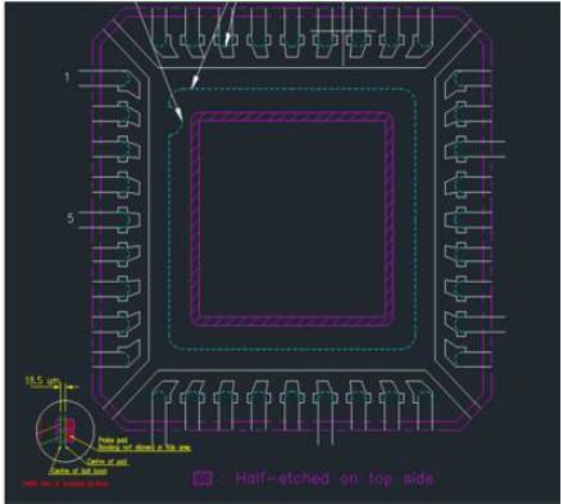
Lead frame Comparison

36L VQFN

ASE



STA



GBNG-16BGIH897 - CCB 4 USB2512B USB2513B USB2514B and USX2064 device families available in 56L \

Affected Catalog Part Numbers(CPN)

USB2512B-AEZG
USB2513B-AEZG
USB2513B-AEYC
USB2514B-AEZG
USB2514B-AEYC
USB2512BI-AEZG
USB2513BI-AEZG
USB2514BI-AEZG
USB2512B-AEZG-TR
USB2513B-AEZG-TR-CD0
USB2513B-AEZG-TR
USB2513B-AEYC-TR
USB2514B-AEZG-TR
USB2514B-AEYC-TR
USX2064-AEZG-TR
USB2512BI-AEZG-TR
USB2513BI-AEZG-TR
USB2514BI-AEZG-TR
USX2064I-AEZG-TR
LAN9500A-ABZJ
LAN9500AI-ABZJ
LAN9500A-ABZJ-TR
LAN9500AI-ABZJ-TR
LAN9500AI-ABZJ-TR-SEU